



IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicant : Shunpei Yamazaki et al. Art Unit : 2823
Serial No. : 09/635,832 Examiner : Fernando Toledo
Filed : August 9, 2000 Confirmation No.: 6795
Title : SEMICONDUCTOR DEVICE HAVING SOI STRUCTURE AND
MANUFACTURING METHOD THEREFOR

MAIL STOP RCE

Commissioner for Patents
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INFORMATION DISCLOSURE STATEMENT

Applicants request consideration of the references listed on the attached PTO-1449 form. Under 37 C.F.R. § 1.98 (a)(2)(ii), only copies of foreign patent documents and/or non-patent literature are enclosed. Copies of any listed U.S. patents or U.S. patent application publications can be provided upon request.

This filing is being made with the filing of a Request for Continued Examination. No fee is required.

Respectfully submitted,

Date: July 20, 2005



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Substitute Form PTO-1449 (Modified)	U.S. Department of Commerce Patent and Trademark Office	Attorney's Docket No. 07977-182002	Application No. 09/635,832
Information Disclosure Statement by Applicant (Use several sheets if necessary)		Applicant Shunpei Yamazaki et al.	
		Filing Date August 9, 2000	Group Art Unit 2823

(37 CFR §1.98(b))

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Examiner Signature	Date Considered
EXAMINER: Initials citation considered. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.	



Substitute Form PTO-1449 (Modified) Information Disclosure Statement by Applicant (Use several sheets if necessary) (37 CFR §1.98(b))	U.S. Department of Commerce Patent and Trademark Office	Attorney's Docket No. 07977-182002	Application No. 09/635,832
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							Yes	No
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							Yes	No
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Other Documents (include Author, Title, Date, and Place of Publication)

Examiner Initial	Desig. ID	Document
	ADDD	Kwok K. Ng; "Complete Guide to Semiconductor Devices"; pp. 164-165; Published by McGraw-Hill, Inc.; 1995

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